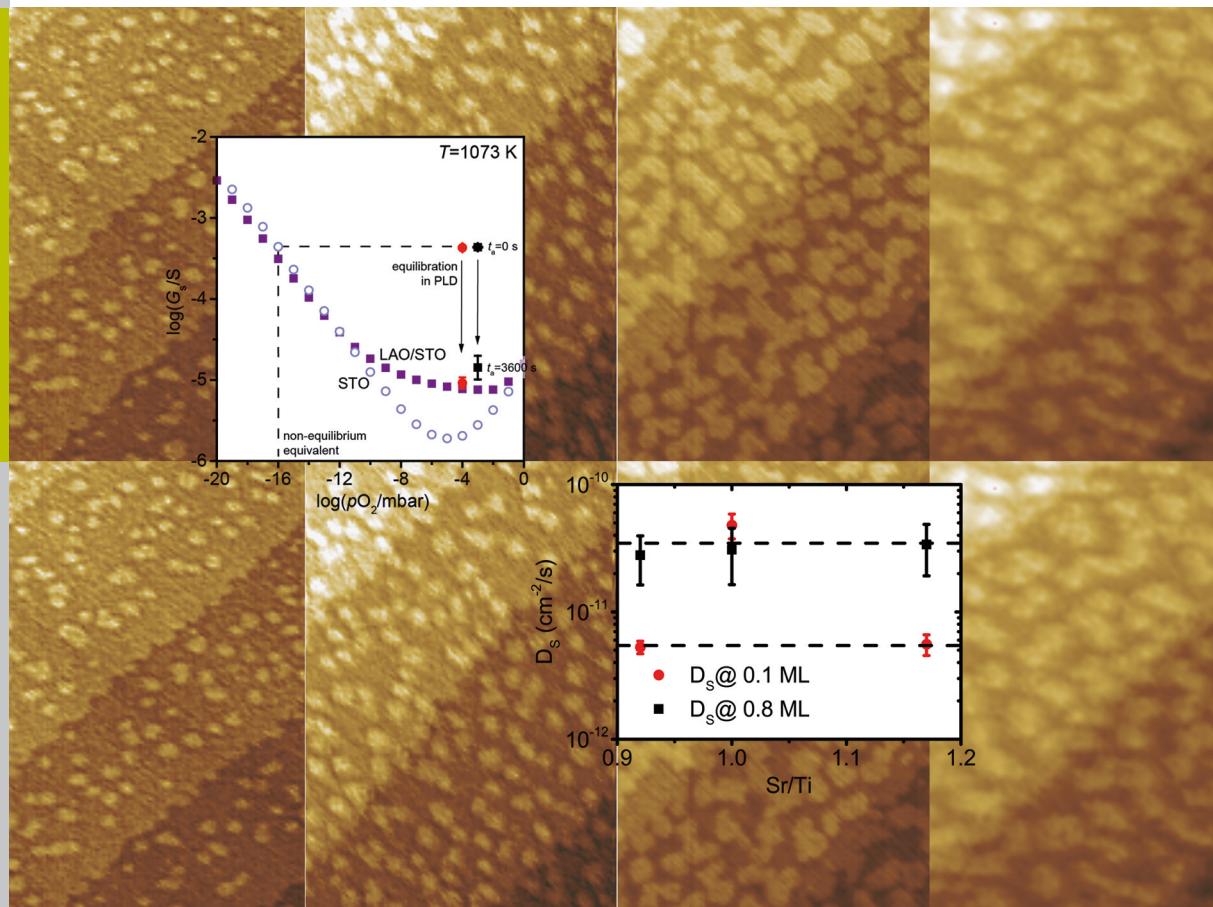


In situ studies of the growth and oxidation of complex metal oxides by pulsed laser deposition

Chencheng Xu



Schlüsseltechnologien /
Key Technologies
Band / Volume 140
ISBN 978-3-95806-204-7

 JÜLICH
FORSCHUNGSZENTRUM

Forschungszentrum Jülich GmbH
Peter Grünberg Institute (PGI)
Electronic Materials (PGI-7)

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Schriften des Forschungszentrums Jülich
Reihe Schlüsseltechnologien / Key Technologies

Band / Volume 140

ISSN 1866-1807

ISBN 978-3-95806-204-7

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